

03/04

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 250227US-2X DIV		SERIAL NO. 18802882 New Div. Appl.	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Shinji IINO, et al.			
				FILING DATE 3/18/2004		GROUP 2829	
				U.S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
Me	AA	5,258,654	11/02/83	P.S. Roberts, et al.			
	AB	5,773,987	06/30/88	T.T. Montoya			
	AC	5,523,833	08/04/88	N. Imazumi, et al.			
	AD	4,851,707	07/25/89	D.S. Lindsay			
	AE	4,477,774	10/1984	Revireux, Michel			
	AF	6,057,694	05/2000	Matsudo			
	AG	5,836,419	08/1999	Chen			
	AH						
	AI						
	AJ						
AK							
AL							
AM							
AN							
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES NO
Me	AO	11-242062	08/07/99	Japan (with English Abstract)			
	AP	JP 84-048038	02/1989	Japan			
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
Me	AW	Mark Bailey, et al. "A Micromachined Array Probe Card-Characterization" IEEE Transactions on Components, Packaging, and Manufacturing Technology-Part B, Vol. 18, No. 1, February, 1995 pgs. 184-191					
	AX						
	AY						
	AZ						
Examiner					<input type="checkbox"/> Additional References sheet(s) attached Date Considered 10/21/04		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							